

IN THE SPECIFICATION

Please amend the specification as follows:

Please amend the first paragraph on page 1 after the title:

CROSS REFERENCE TO RELATED APPLICATIONS

This patent application is related to U.S. Patent Application Serial Number 10/789,895 entitled METHOD AND SYSTEM FOR AGGREGATING AND COMBINING MANUFACTURING DATA FOR ANALYSIS, to Naoki Toyoshima and Yuko Maeda, assigned to Micron Technology, Inc., and incorporated herein by reference.

Please amend Table A on page 12, as follows:

Process	Time of Event	Sampled Value	Calculated Sampled Value assigned to Production Lot
Sample 1	tS_1	S_1	
Lot 1	tL_1		$L_1 = 1/(tS_2 - tS_1) \{S_1(tS_2 - tL_1) + S_2(tL_1 - tS_1)\}$
Lot 2	tL_2		
Lot-i	tL_i		$L_i = 1/(tS_3 - tS_2) \{S_2(tS_3 - tL_2) + S_3(tL_2 - tS_2)\}$
Lot-i+1	tL_{i+1}		
Lot-i+2	tL_{i+2}		
Sample 2	tS_2	S_2	
Lot - j	tL_j	L_j	$L_j = 1/(tS_3 - tS_2) \{S_2(tS_3 - tL_j) + S_3(tL_j - tS_2)\}$
Lot - j+1			
Lot - j+2			
Lot - j+3			
Lot - j+4			
Lot - j+5			
Lot - j+6			
Sample 3	tS_3	S_3	
Lot - k	tL_k	L_k	$L_k = 1/(tS_4 - tS_3) \{S_3(tS_4 - tL_k) + S_4(tL_k - tS_3)\}$
Lot - k+1			
Lot - k+2			
Lot - k+3			
Lot - k+4			
Lot - k+5			
Sample 4	tS_4	S_4	
⋮	⋮	⋮	⋮